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## PATENT ABSTRACTS OF JAPAN

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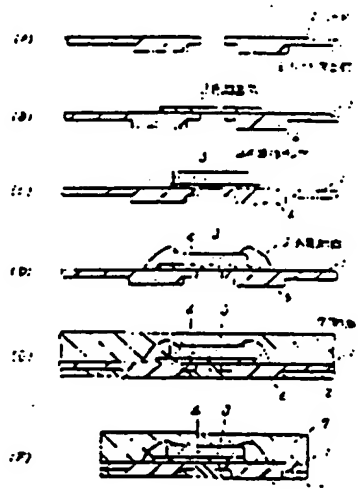
(21)Application number : 62-211993  
 (22)Date of filing : 26.08.1987

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**(54) SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF****(57)Abstract:**

**PURPOSE:** To obtain a highly accurate and highly reliable semiconductor device by placing a semiconductor chip through an insulating substrate on one group of highly accurate metal leads, connecting the leads to fine metal wirings, and transfer molding them.

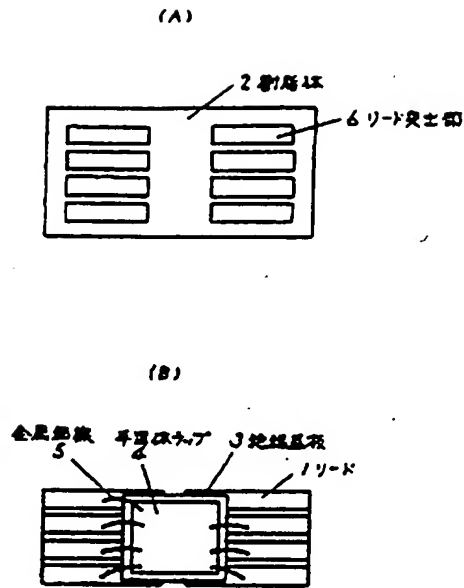
**CONSTITUTION:** A thin resin plate 3 is attached to leads 1 having protrusions 6, and electrodes on a semiconductor chip 4 are connected to the leads 1 by fine metal wirings 5. Then, the leads except the protrusions 6 are sealed with resins 2, 7, shape and size are determined and cut. According to this structure, a small-sized and thin semiconductor device having high dimensional accuracy and reliability is obtained without complicated structure like a both-side substrate only by employing metal leads of special shape at part, and is preferably adapted for an IC.

**LEGAL STATUS**

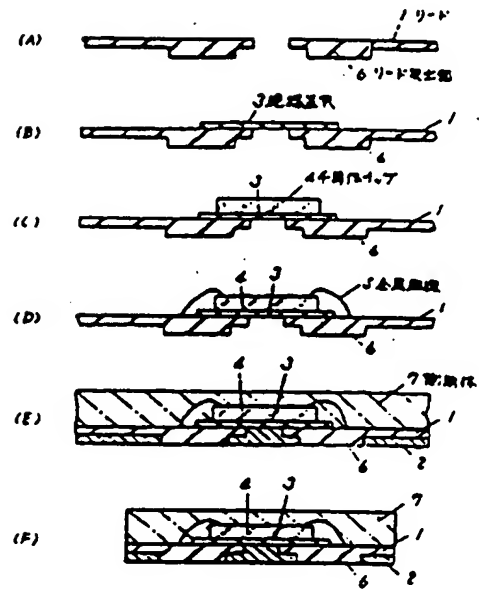
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第 2 図



第 3 図



第 4 図

